

# Electropolishing of large copper substrates for FCC

**FCC-ee 400 MHz double cell**

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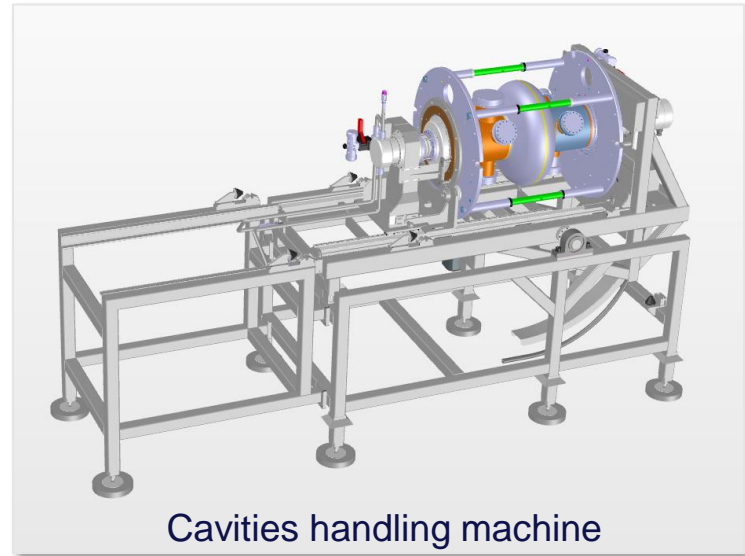
## Preparation for the 2-cells 400 MHz FCC-ee cavities

- Main challenges & strategies

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# Tools and expertise

## Electropolishing set-up & Interfaces



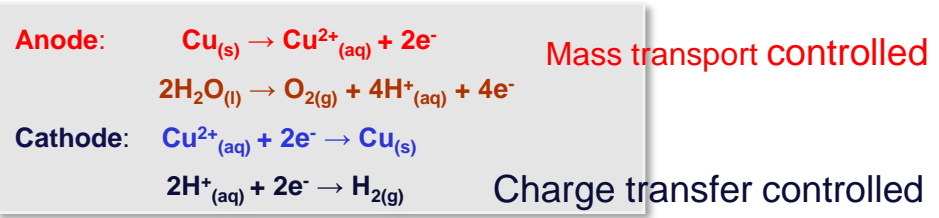
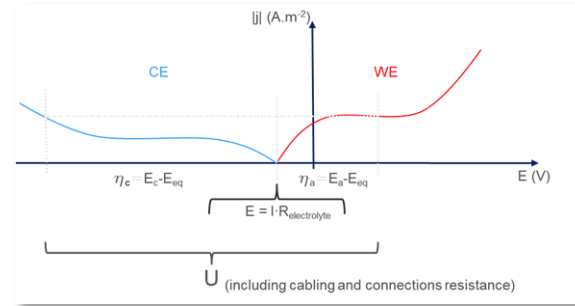
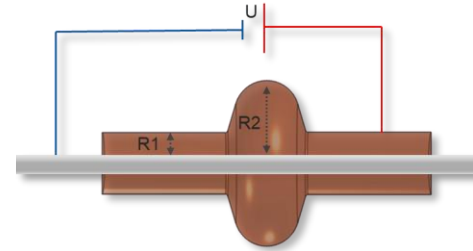
# Tools and expertise

- Simulation

## # working parameters

$$j = f(U, T, v_b, S_c/S_a, \sigma_l, [b])$$

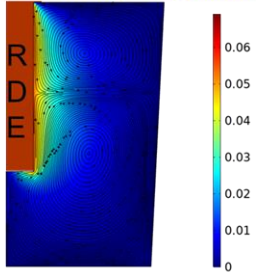
- j, Current density
- **U**, Overall applied tension
- **T<sub>b</sub>**, Bath temperature
- **v<sub>b</sub>**, Bath fluid dynamics
- S<sub>c</sub>/S<sub>a</sub>, **Cathode geometry** & Cathodic/Anodic surface ratio
- σ<sub>l</sub>, Bath conductivity
- [b], Bath composition



# Tools and expertise

- Simulation

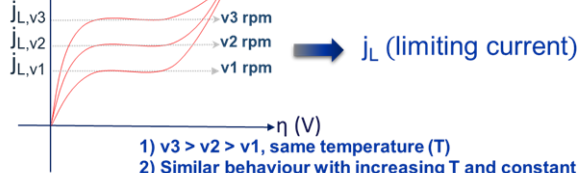
Bath velocity magnitude (m/s)



Shear rate

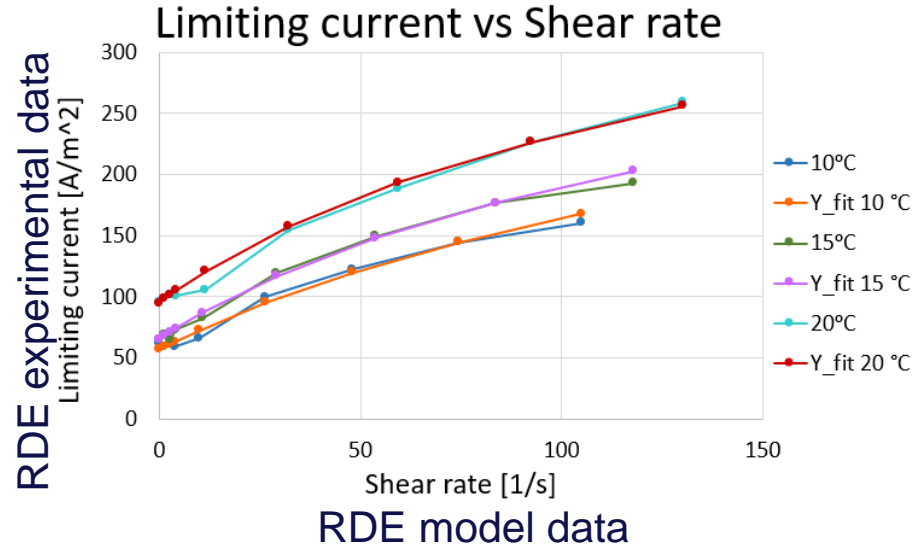
$$\tau = \sqrt{\left(\frac{\partial u}{\partial z}\right)^2 + \left(\frac{\partial v}{\partial z}\right)^2}$$

$j$  (A.m<sup>-2</sup>)



- 1)  $v3 > v2 > v1$ , same temperature (T)
- 2) Similar behaviour with increasing T and constant rpm

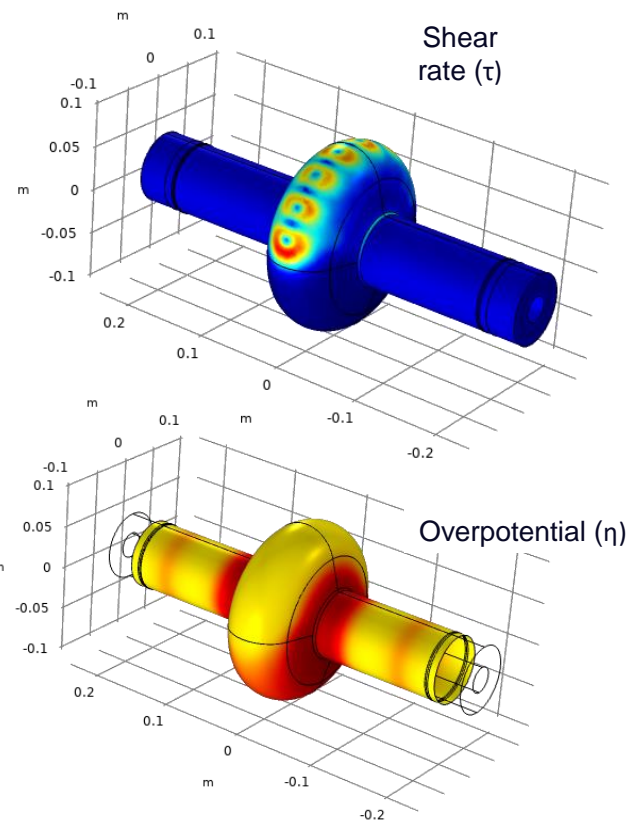
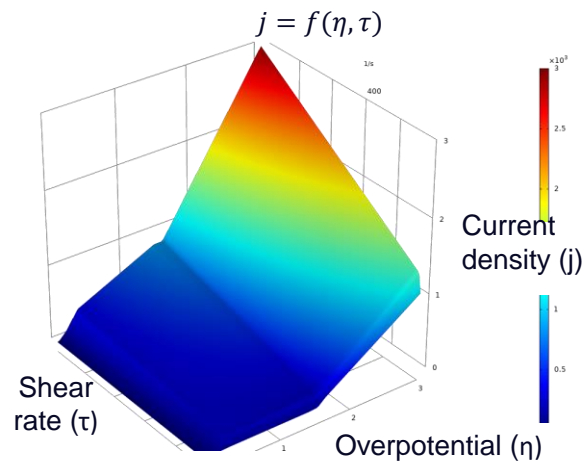
Shear rate ( $\tau$ ) is the rate of change in velocity at which one layer of fluid passes over an adjacent layer



# Tools and expertise

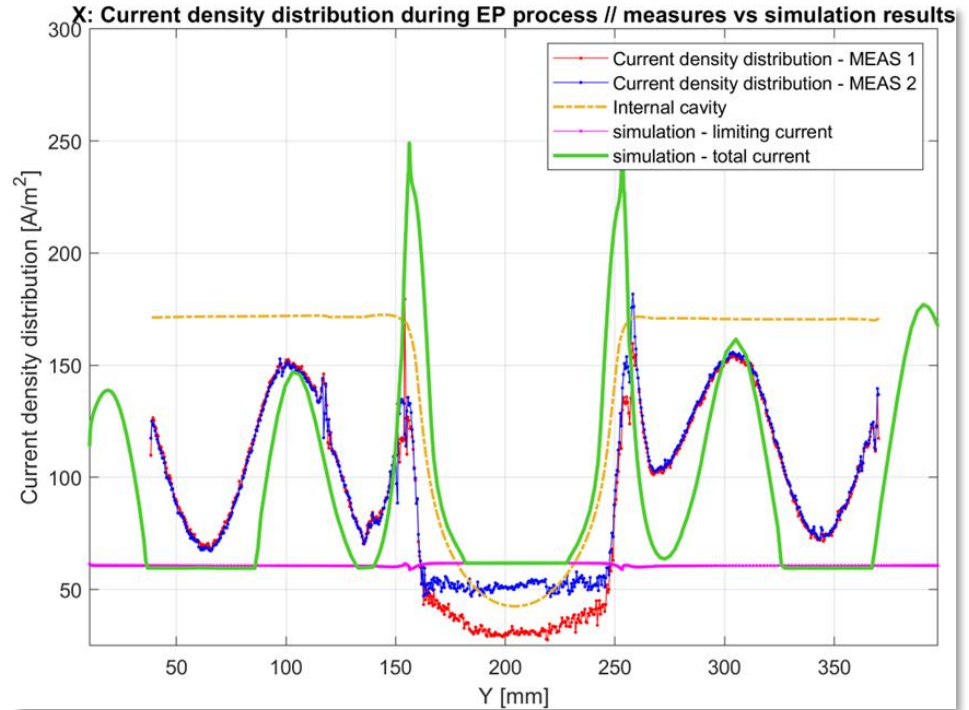
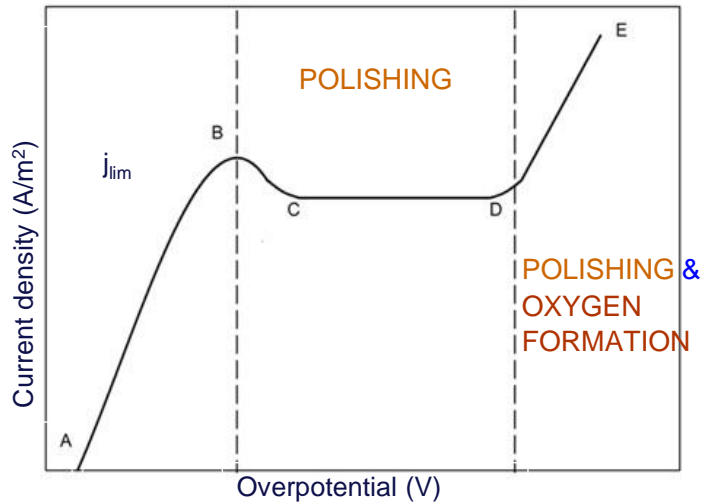
- Simulation

Creation of a new anodic current density function to be used for any geometry, using the results obtained with the RDE:



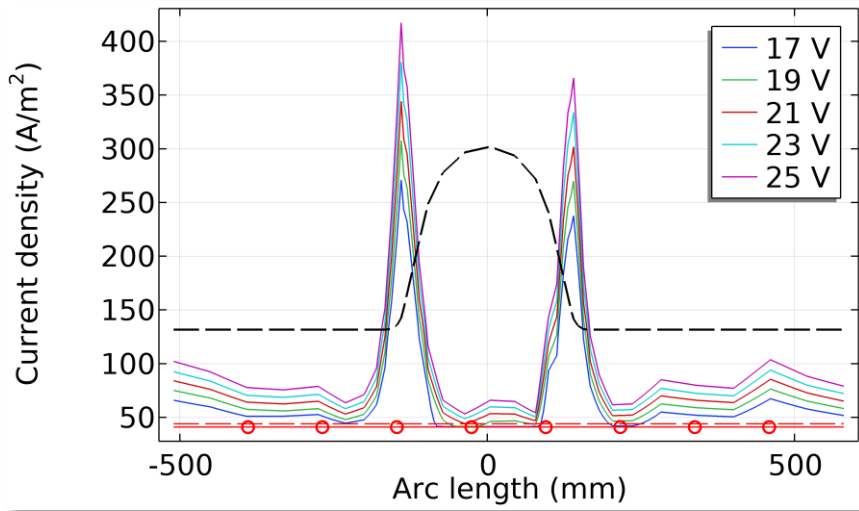
# Simulation vs Real data

- Benchmarking on 1.3 GHz copper monocell



# Simulation vs Real data

- Data from simulation:  
**400 MHz** Current density distribution at 10 °C



Simulation total current, corrected to estimated wet surface: **84 A** at 21 V

- Data from **400 MHz** monocell processing

Cavity	Tension / V	Current / A	Temperature / °C *
PC04#1	21	81.8	15.4
PC04#2	21	72.5	14.0
PC06#1	21	75.0	15.2
PC06#2	21	75.9	14.8

\*) Temperature readings from the chemical facility are not in line with the ones measured on the test cavity (~10 °C). dT within the chemical facility is below 1.6 °C.

Average polishing rate: **0.1 μm/min**

# Main issues and achievements

1<sup>st</sup> Ever electropolishing of a 400 MHz monocell copper cavity



1<sup>st</sup> Ever electropolishing of a 400 MHz LHC monocell copper cavity



# Main issues and achievements

Main issue: Passivate the copper

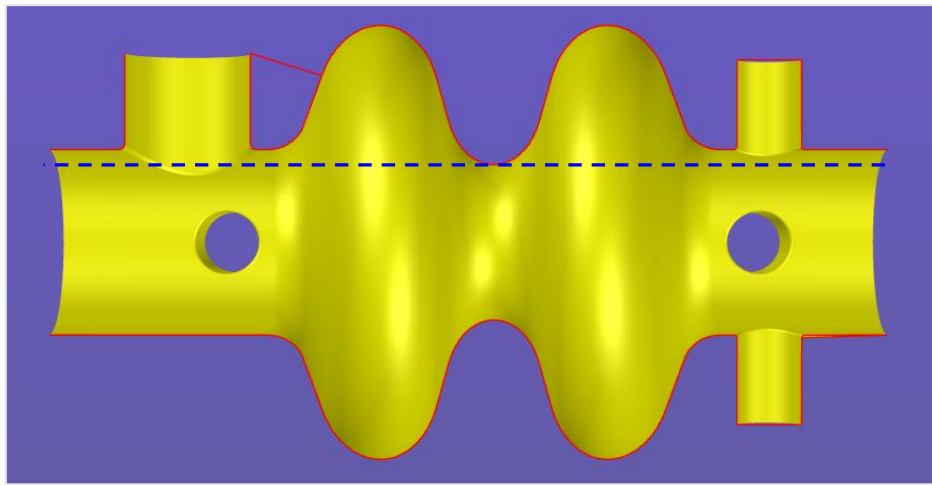


Neutralisation before disassembly

# Preparation for the 2-cells 400 MHz FCC-ee cavities

## Main challenges

- Power input (+ surface & + distance)



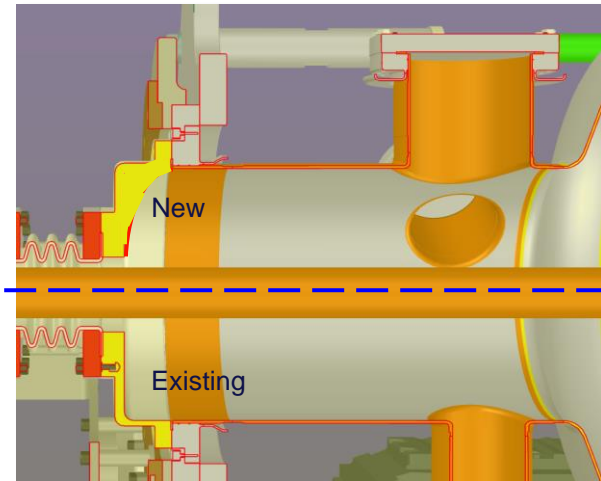
## Strategy

- Cathode optimisation
- Increase bath flow
- Exploit existing working window

# Preparation for the 2-cells 400 MHz FCC-ee cavities

## Main challenges

- Passivation of copper



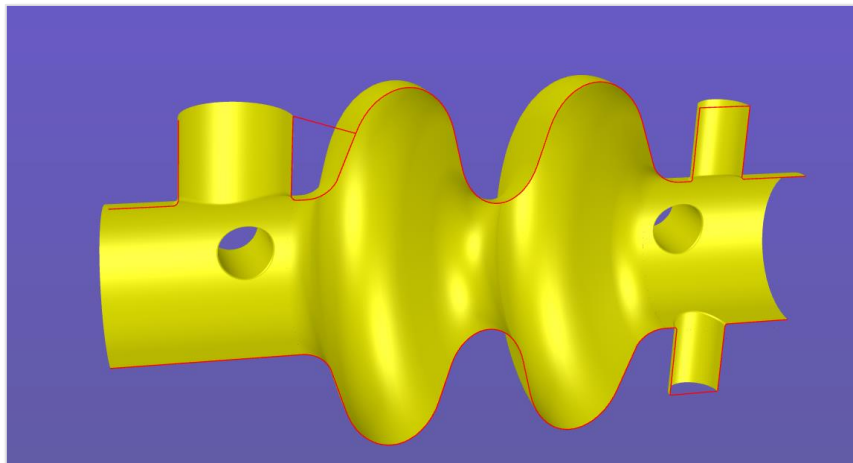
## Strategy

- Reduce retentions
- Reduce back flow
- Keep neutralisation step

# Preparation for the 2-cells 400 MHz FCC-ee cavities

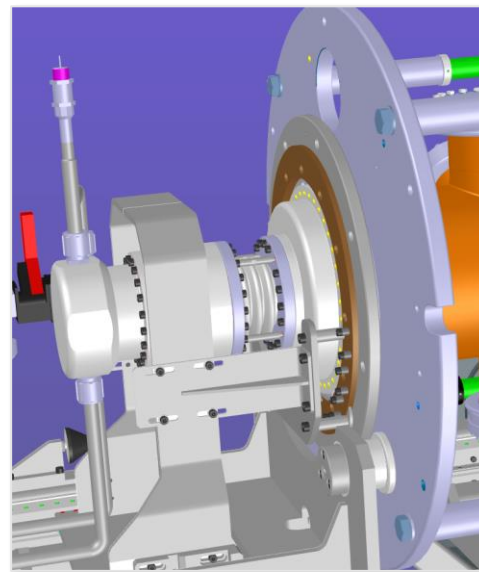
## Main challenges

- Electropolishing of ports



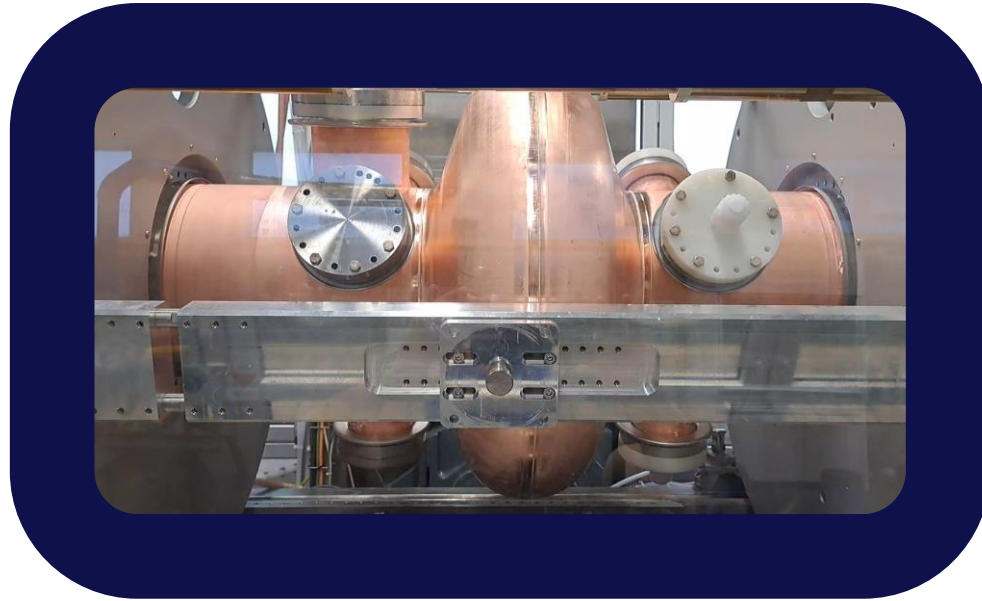
## Strategy

- Assemble 2<sup>nd</sup> contact ring



# Conclusions

- Electropolishing process is well mastered
- Data from 400 MHz monocell processing ensures 2-cell geometry EP feasibility
- Main challenge remains the copper surface passivation
- Impact of non electropolished (EP) ports still to be assessed



Thank you for your attention